



“ELECTRONIC PACKAGING MATERIALS FOR SIC POWER MODULES”

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TODAY'S AGENDA

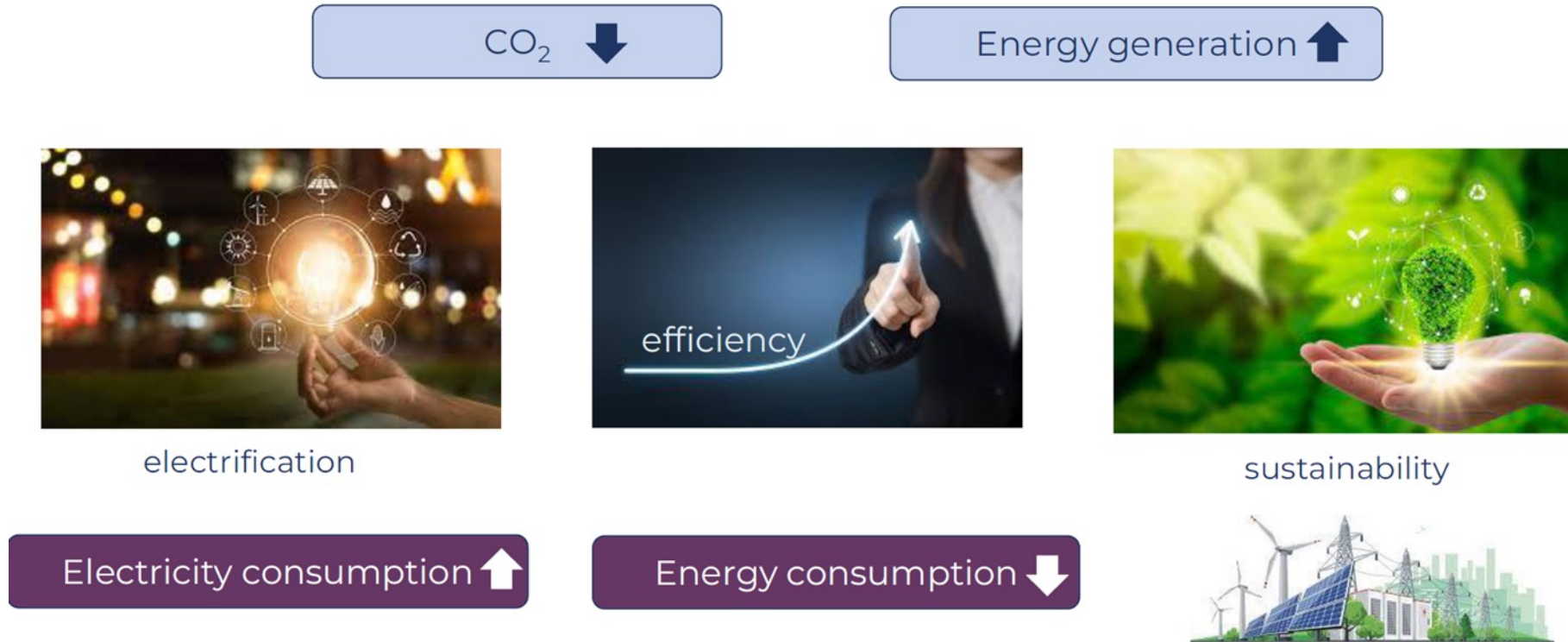
- 1 | THE WORLD BECOMES ELECTRIC
- 2 | REQUIREMENTS FOR POWER MODULE CHANGE
- 3 | SUBSTRATE TECHNOLOGIES: DCB VS AMB SUBSTRATES
- 4 | DIE ATTACH AND MODULE ATTACH TECHNOLOGIES: SINTER VS SOLDER
- 5 | DIE TOP CONNECTIONS: AL VS CU DIE TOP CONNECTIONS
- 6 | CONCLUSION



**THE WORLD BECOMES
ELECTRIC**

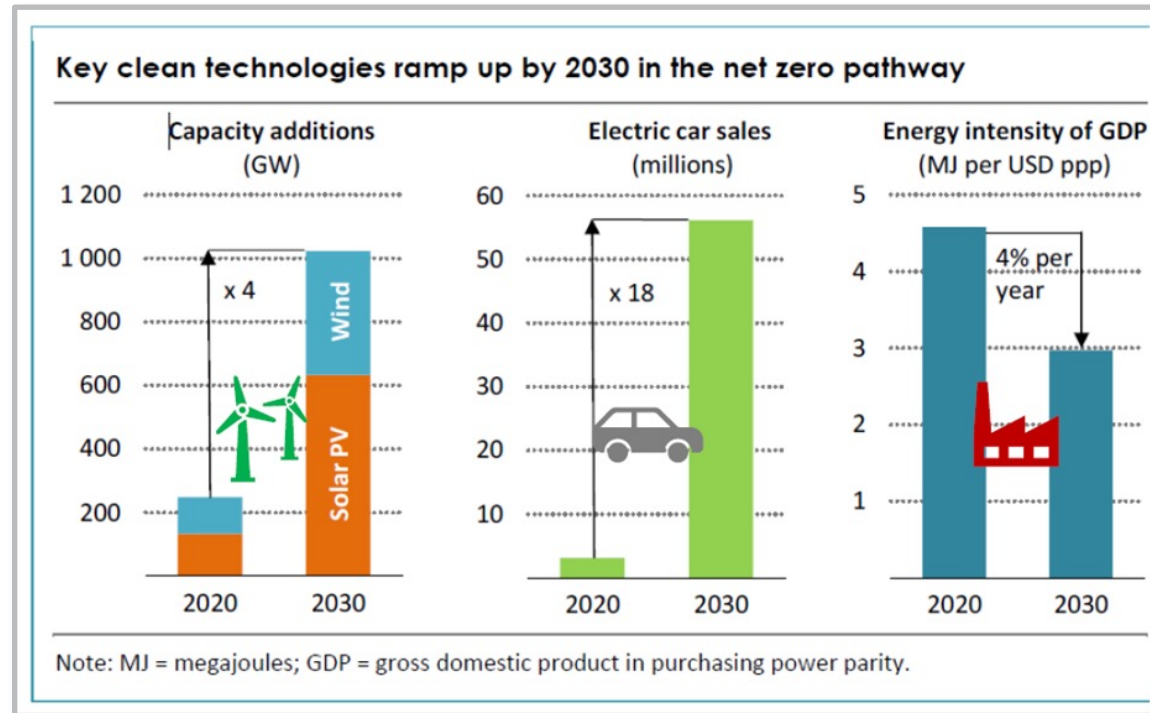
POWER ELECTRONICS HAS SIGNIFICANT POTENTIAL FOR CO₂ REDUCTION AND IS INEVITABLE TECHNOLOGY TOWARDS ZERO EMISSION WORLD

3 MAIN DRIVERS FOR POWER MARKET GROWTH

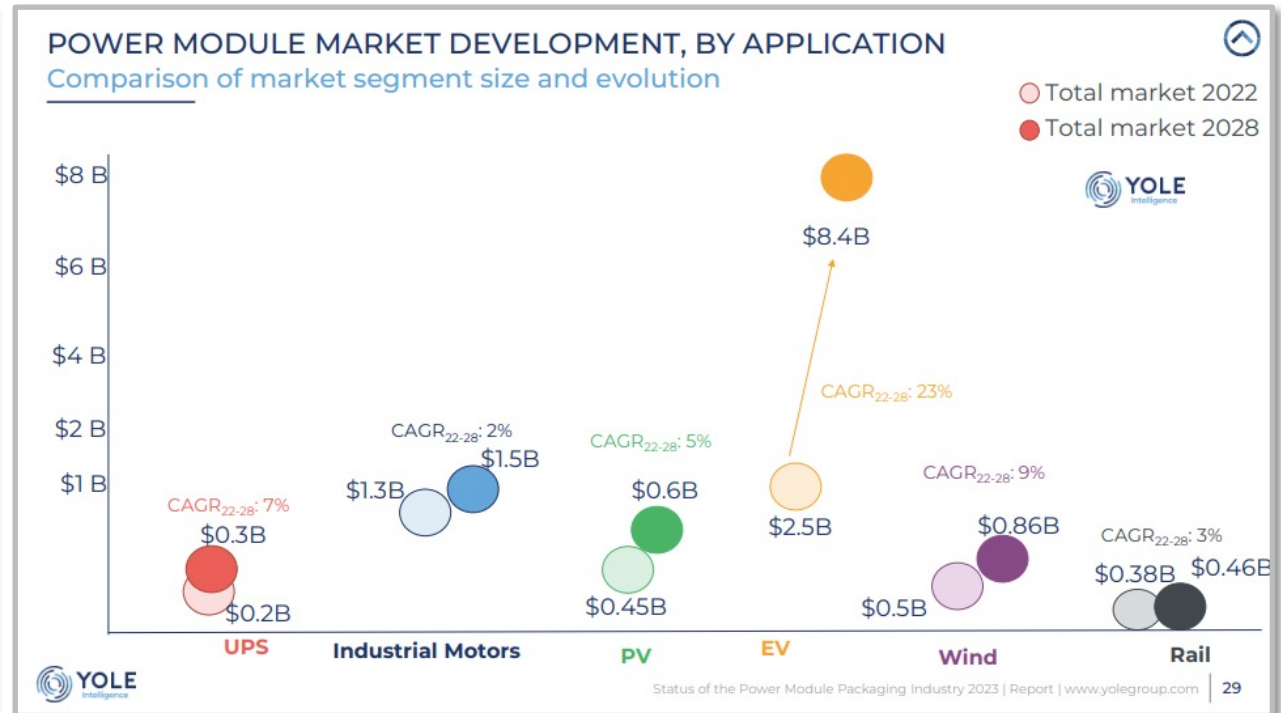


Source: Yole Report, Status of the Power Module Packaging Industry 2024

Power Electronics play a **key role** in today's increasingly electrified world...



Source: Yole Report Status of the Power Electronic Industry 2023



....from generation to distribution and consumption in industrial, automotive, renewable energies, appliances ...



REQUIREMENTS FOR POWER MODULE CHANGE

TRENDS IN POWER MODULE PACKAGE



Si to WBG



**Higher Power
Density**



**Higher
Reliability**



**Lower Total
Cost of
Ownership**



**Reduction
Weight &
Volume**

POWER SEMICONDUCTORS AND NEED FOR NEW PACKAGING MATERIALS SOLUTIONS

Smaller and Thinner Dies

Increased Power Density

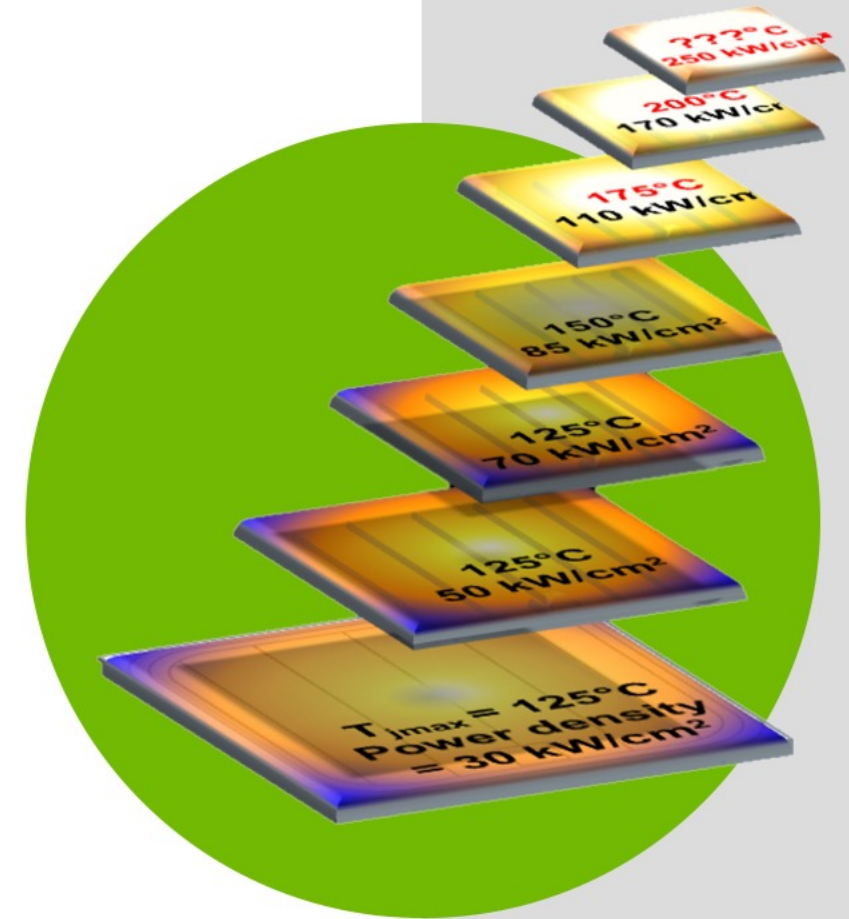
Higher Operating Temperature

Benefit through smaller dies

- Reduction of chip size / cost
- Lower losses / higher efficiency
- Increase of power & current density per chip

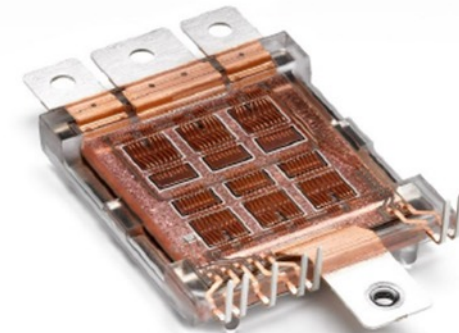
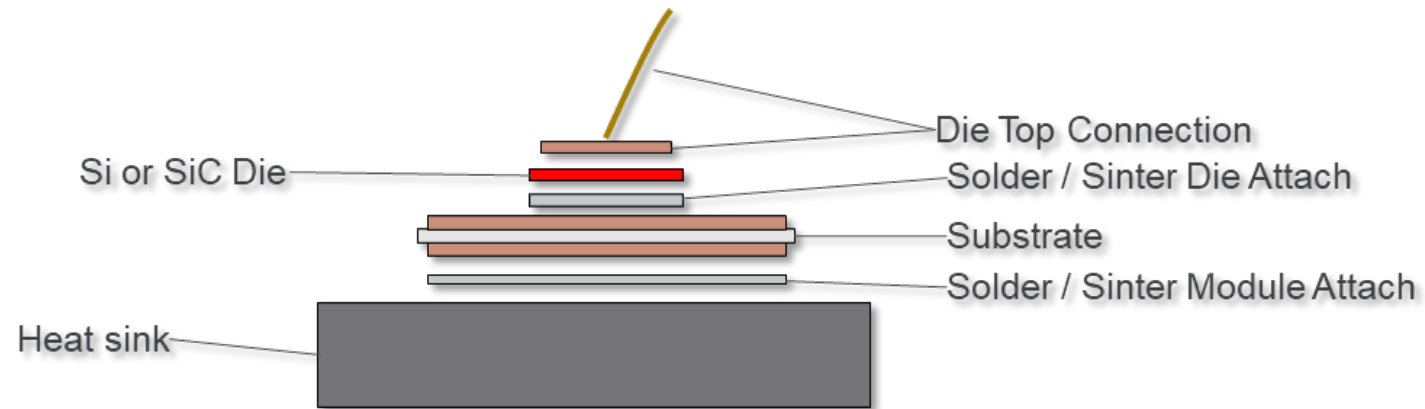
Packaging challenges

- Increased power loss per chip area requires materials with better heat dissipation
- More power needs better current carrying capability of packaging materials
- Increased operating temperatures and reliability challenges



Source: Challenges of New Packaging Solutions for Power Modules, Prof. R. Eisele - FH Kiel, Anton Miric - Heraeus Electronics GmbH & Co. KG, PCIM Conference May 2021

SIMPLIFIED POWER MODULE PACKAGE



Power module platform compatible both with IGBT and SiC technologies
(Source: Danfoss)

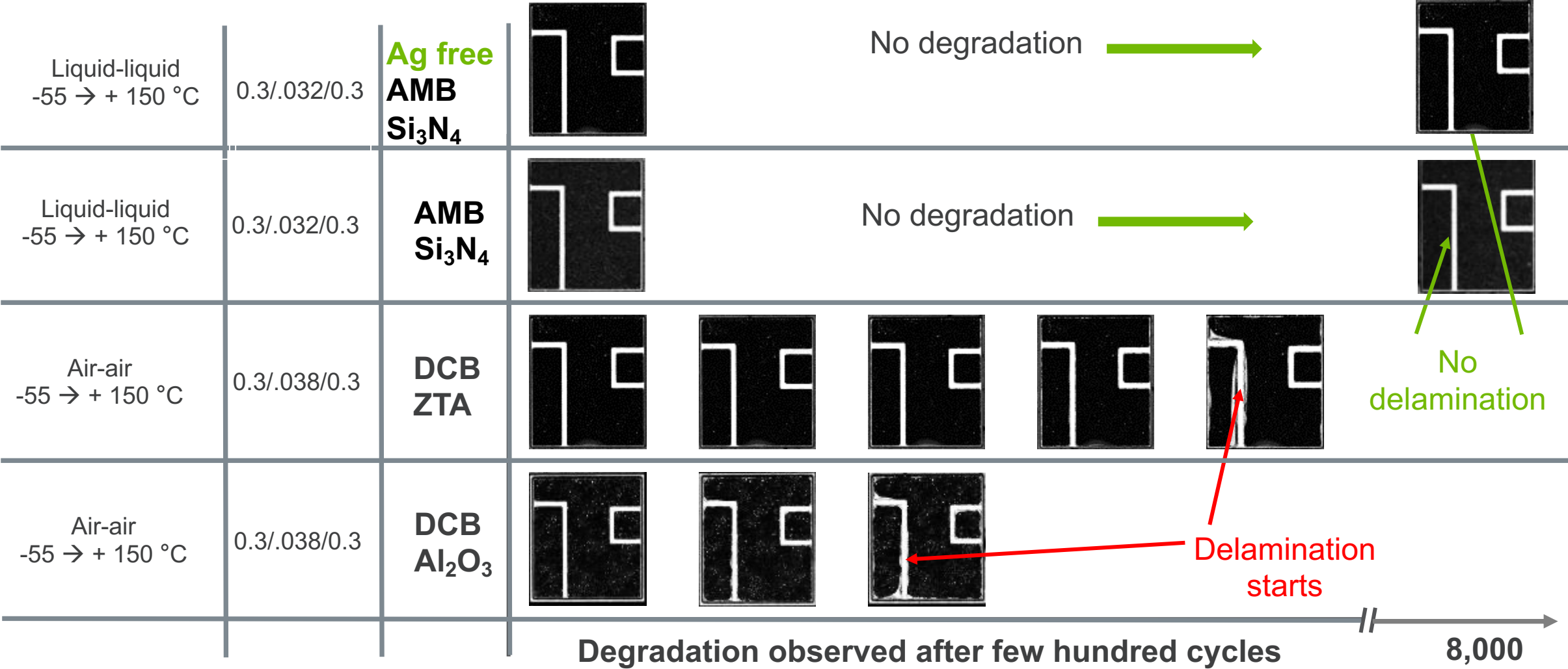


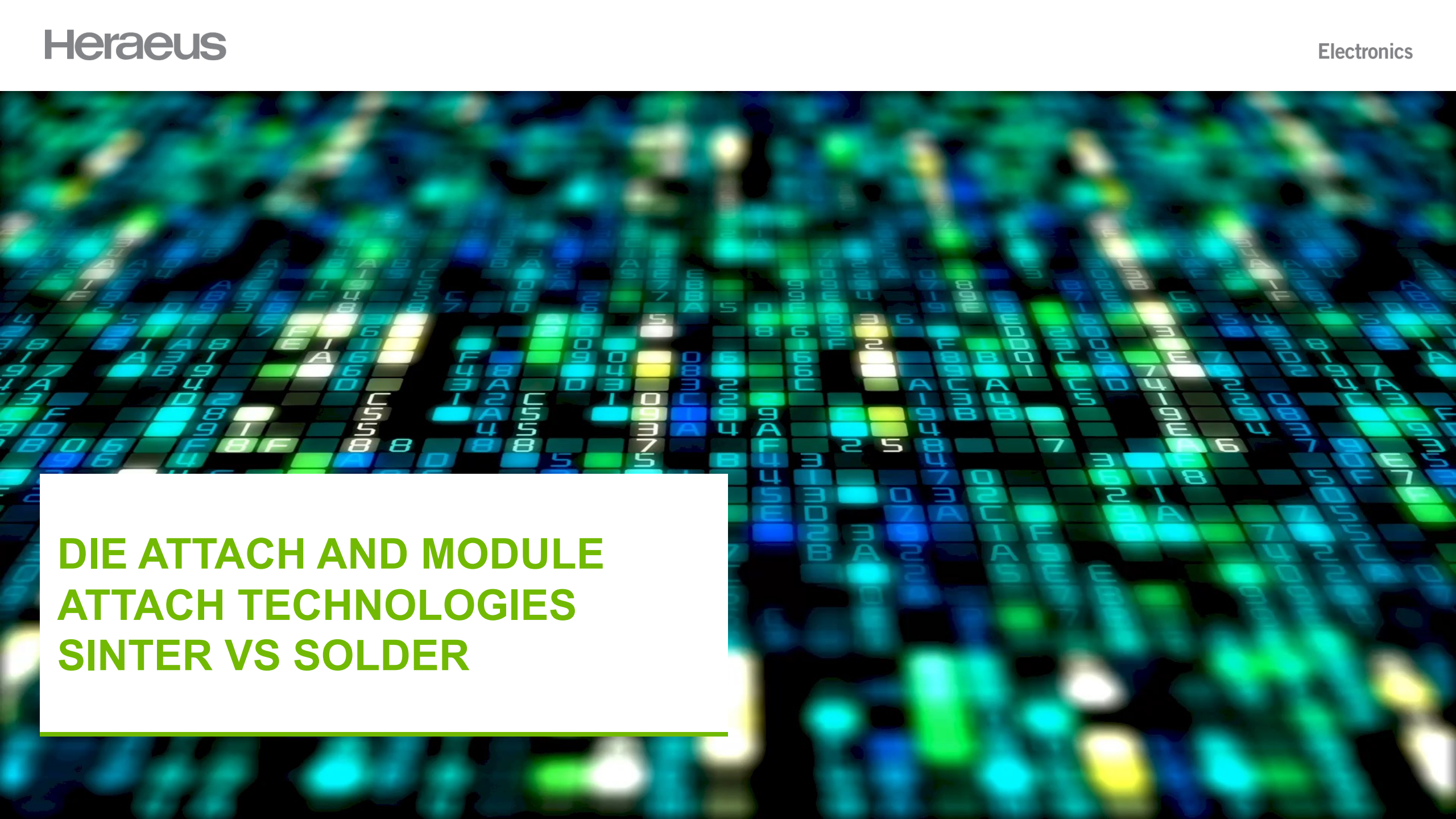
SUBSTRATE TECHNOLOGIES DCB VS AMB SUBSTRATES

WHY DO WE NEED **NOVEL SOLUTION** FOR SUBSTRATE?*Trend of SiC
power package**Requirements
for MCS material* *Al_2O_3 DCB* *Si_3N_4 AMB*

High operation T	Low CTE mismatch with SiC (~ 4 ppm)	~ 7 ppm	→	~ 2.5 ppm
High power density	High thermal conductivity	~ 25 W/m K	→	~ 80 W/m K
High reliability	High resistance to fracture	~ 3 MPa·m ^{1/2}	→	~ 7 MPa·m ^{1/2}

Si₃N₄ SUBSTRATE IS THE **MOST SUITABLE** SOLUTION FOR SIC PACKAGE



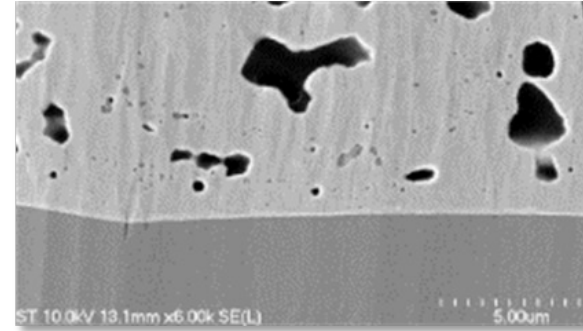
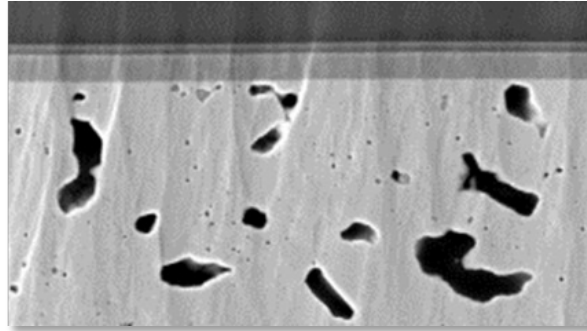
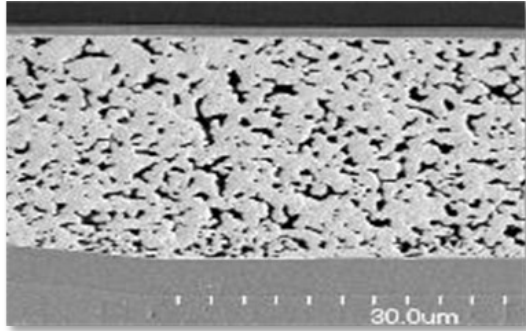


DIE ATTACH AND MODULE ATTACH TECHNOLOGIES SINTER VS SOLDER

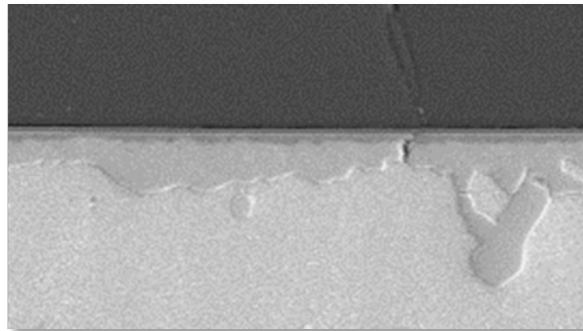
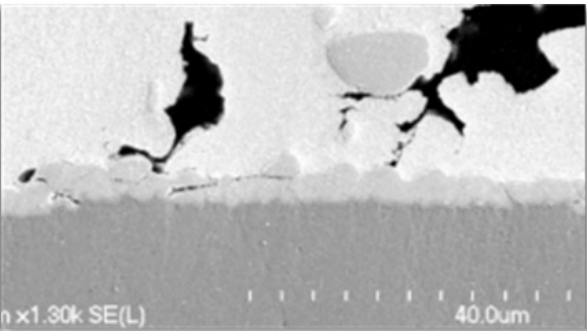
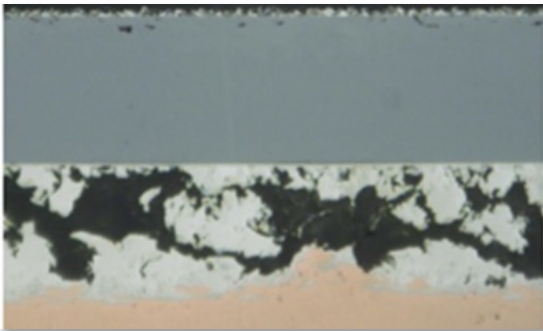
WHY DO WE NEED **NOVEL SOLUTION** FOR DIE AND MODULE ATTACH?*Trend of SiC
power package**Requirements
for DA material**Solder**Ag Sinter*

High operation T	High melting point	~ 220 °C	→	~ 960 °C
High power density	High thermal conductivity	~ 50 W/m K	→	~ 250 W/m K
High reliability	High creep resistance	$T_w/T_m > 0.7$	→	$\sim T_w/T_m < 0.3$

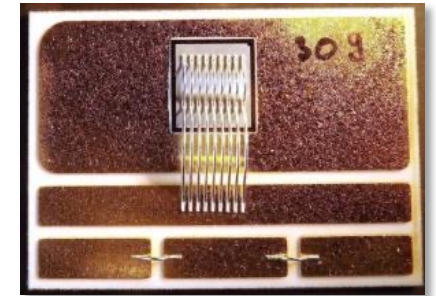
BENEFIT OF DIE-SINTERING - **NO DEGRADATION**



Sintered Module with AlCu-Wire after 130.000 Power Cycles



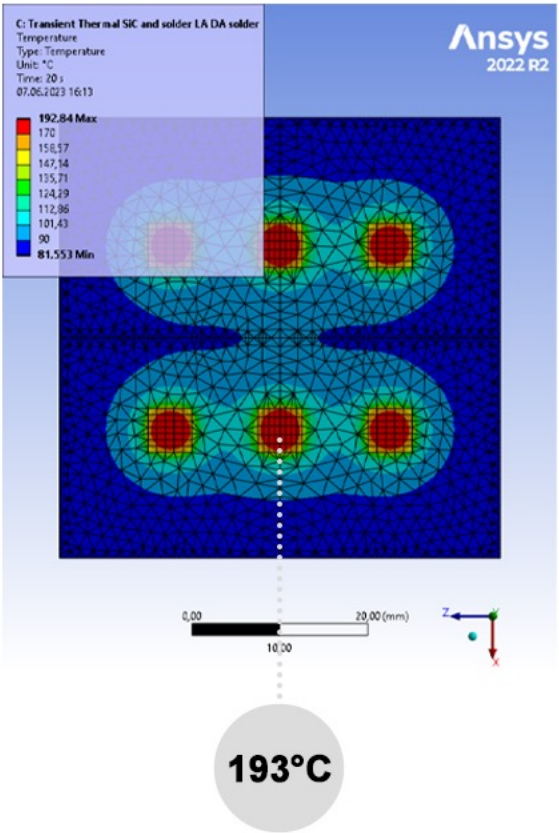
Soldered Module with AlCu-Wire after 56.000 Power Cycles



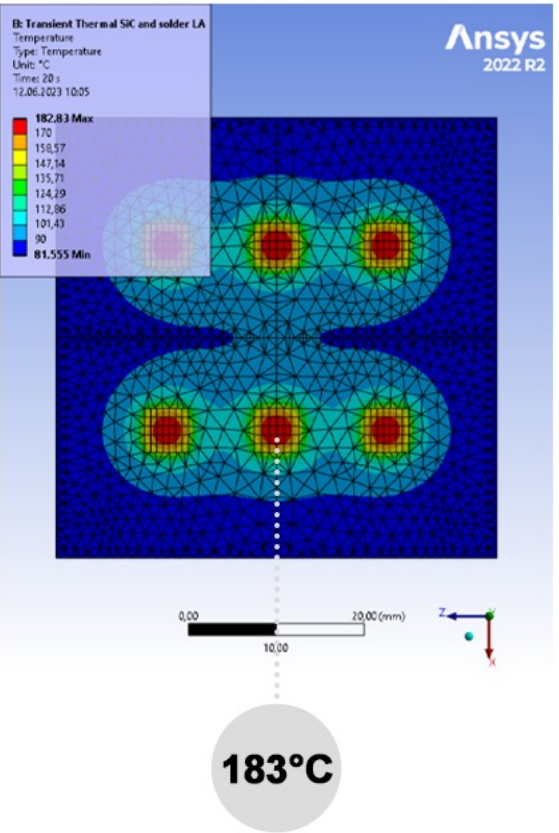
Test parameters:
 $T_{on} = T_{off} = 15 \text{ sec}$
 $T_C = 40^\circ\text{C}$
 $dT_{max} = 110 \text{ K}$
 $T_{max} = 150^\circ\text{C}$

BENEFIT OF MODULE **SINTERING** – HEAT DISSIPATION

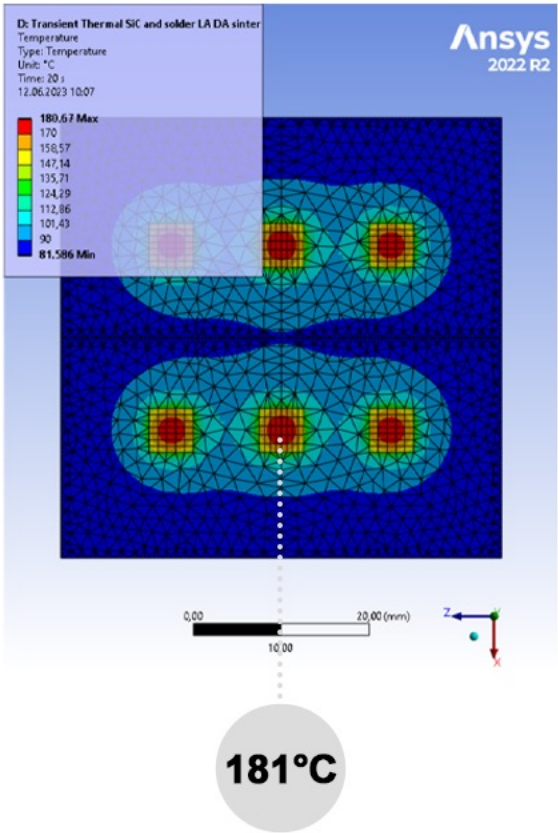
Die Attach: soldered
Module Attach: soldered



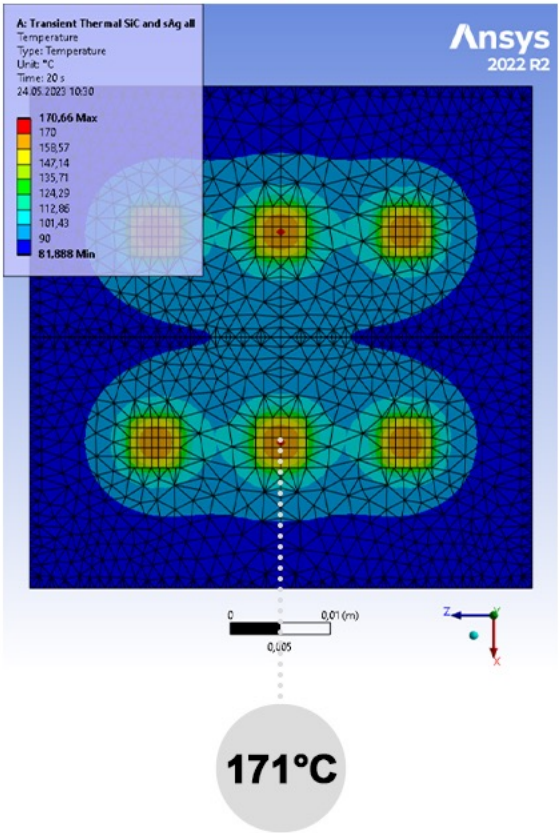
Die Attach: sintered
Module Attach: soldered



Die Attach: soldered
Module Attach: sintered

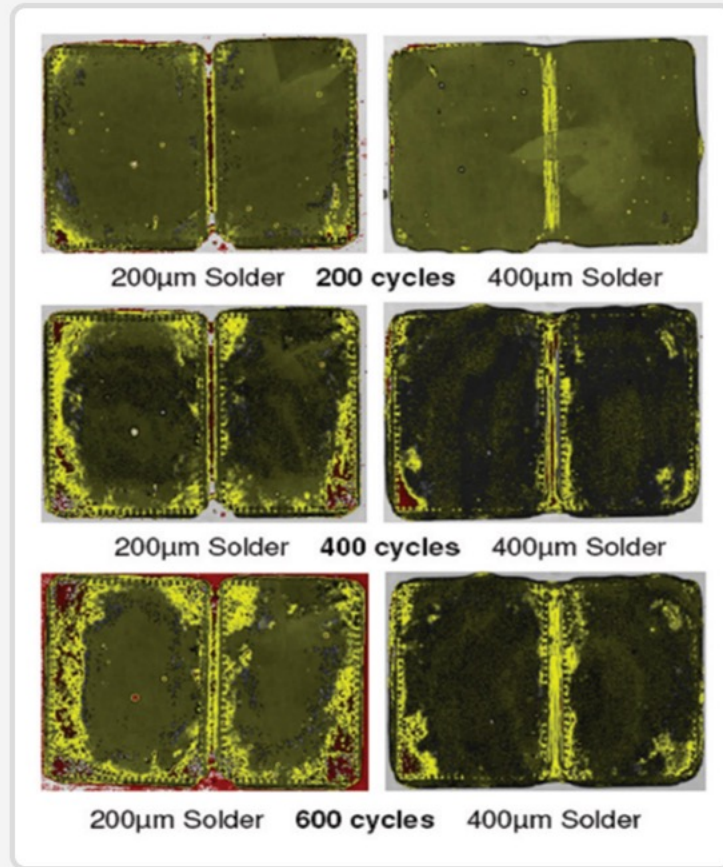


Die Attach: sintered
Module Attach: sintered

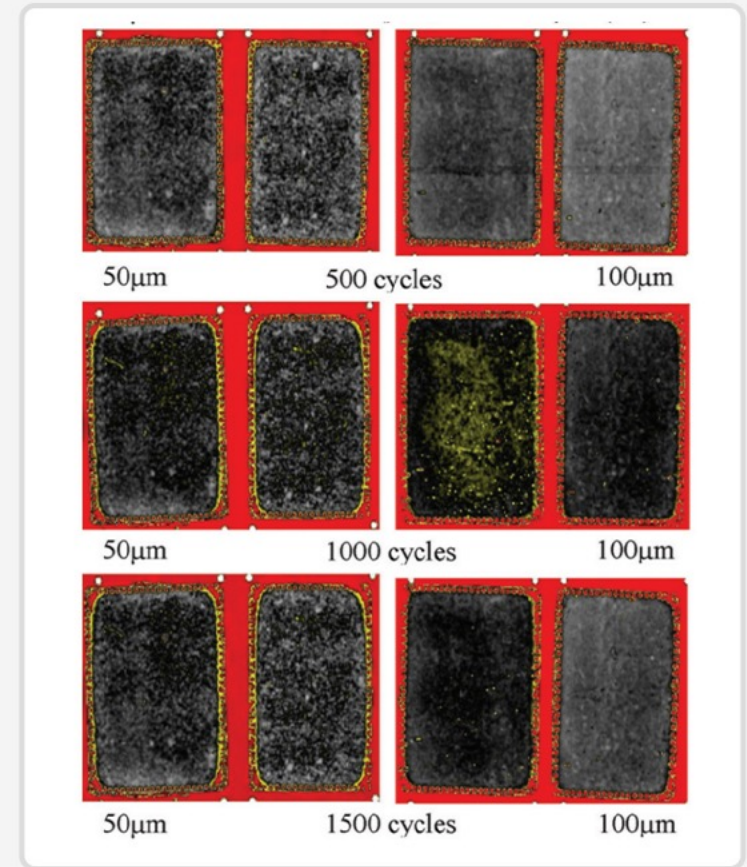


BENEFIT OF MODULE **SINTERING** – RELIABILITY

Module soldered



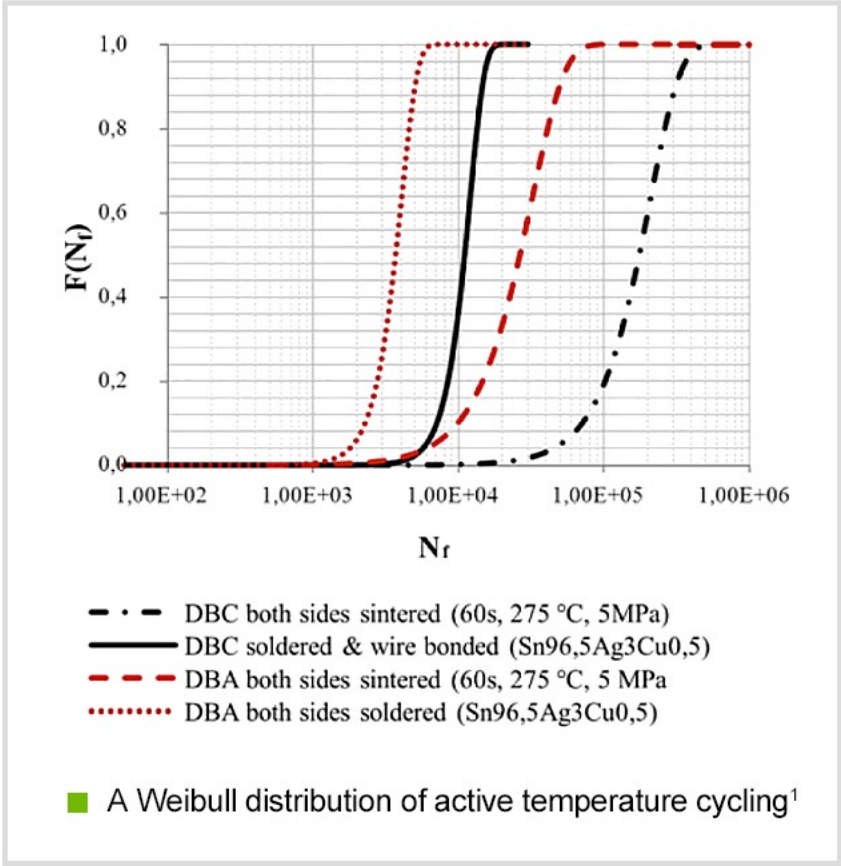
Module sintered



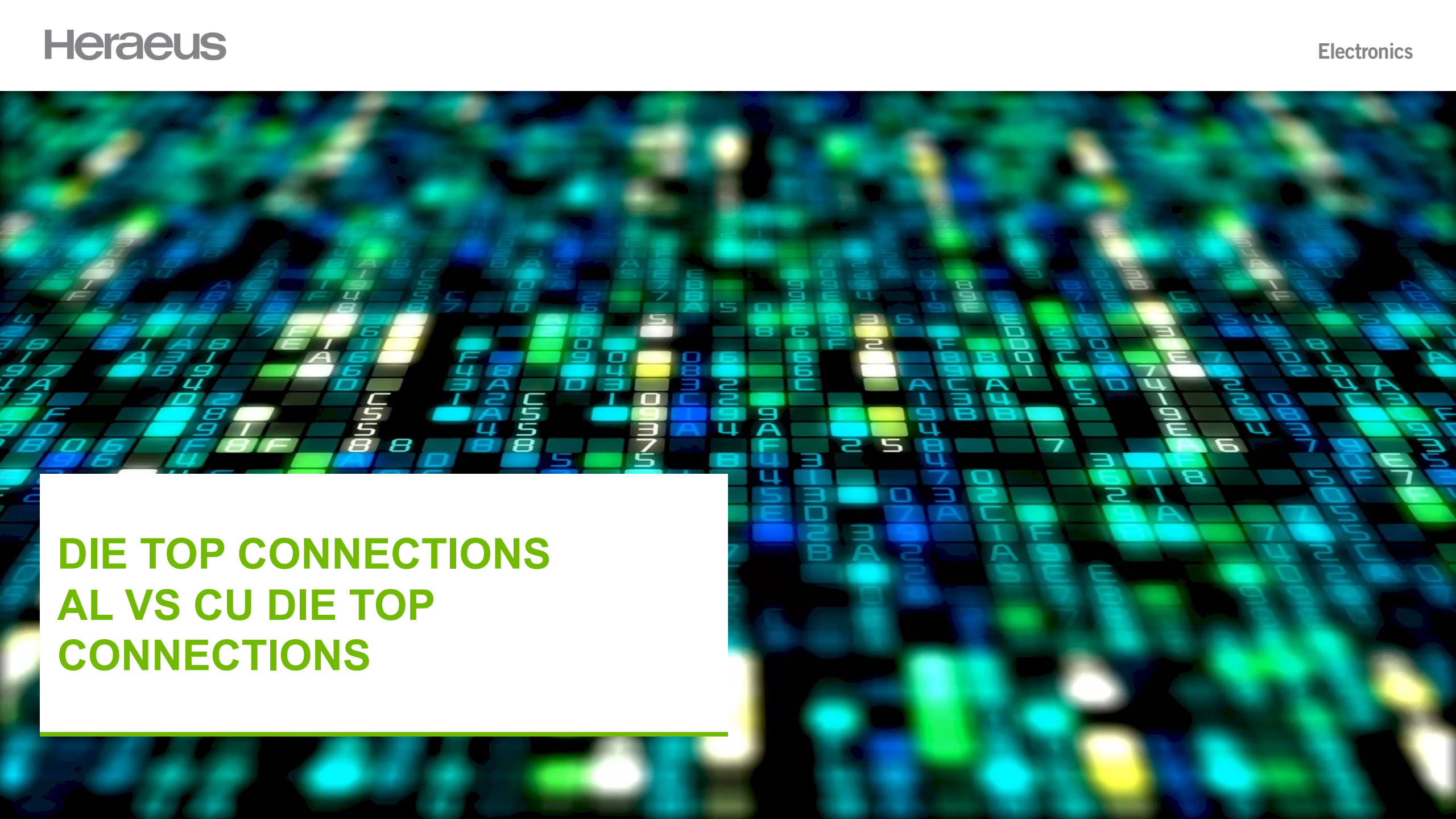
ALL SINTERED MODULE HAS A SIGNIFICANTLY **INCREASED LIFETIME**

Materials properties	Solder paste	Sinter paste
Electrical resistivity (mΩ/cm)	0.01-0.03	≤0.008
Thermal conductivity (W/m·K)	20-50	>200
CTE (ppm/K)	25-30	19
Residue free	No	Yes

■ Higher reliability at TCT could be achieved by Ag sintering



Source: Innovative Material Packaging Solutions for superior Power Electronics Devices, EDPC Conference Nov. 2016, Nürnberg, A. Miric, Dr. Frank Osterwald, P. Dietrich, A.S. Klein, A. Hinrich



DIE TOP CONNECTIONS AL VS CU DIE TOP CONNECTIONS

WHY DO WE NEED **NOVEL SOLUTION** FOR DIE TOP CONNECTION?***Trend of SiC
power package******Requirements for die
top interconnection
material******Al Wire******Cu Wire***

High operation T	High thermal conductivity	~ 220 W/m K	→	~ 390 W/m K
High power density	High electrical conductivity	~ $3.5 \cdot 10^7$ S/m	→	~ $6.0 \cdot 10^7$ S/m
High reliability	High melting point	660 °C	→	1084 °C
	High yield stress, high ultimate stress	~30 MPa and 50 MPa	→	~80 MPa and 300 MPa

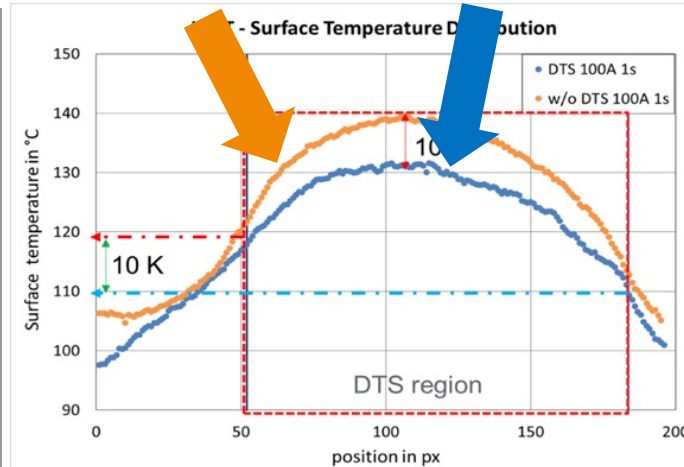
POWER CYCLING SOLDER & AL WIRE VS. SINTER & CU WIRE

SOLDER / AL WIREBONDING

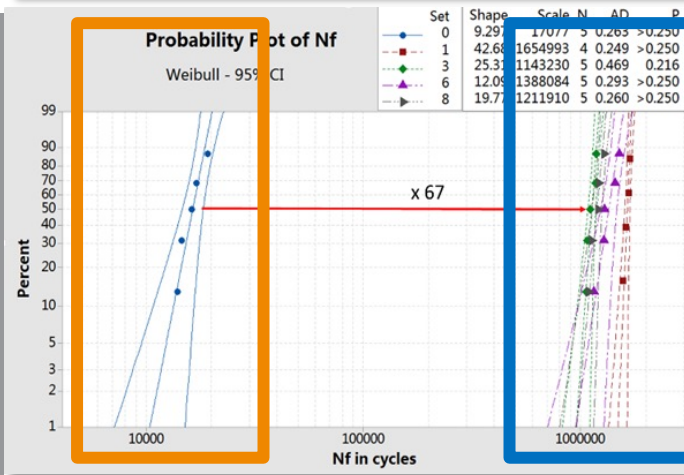
- › **Bond wires:**
400µm Al wire
- › **Die attach:**
SnAg solder



TEMPERATURE



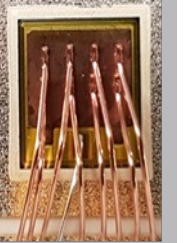
RELIABILITY



Powercycling: I(const.)=136A/ton=1s, toff=2s, DT=130K, Tmax=175°C, failure 5% increase VCE

SINTER / CU WIREBONDING

- › **Bond wires:**
400µm Cu wire
- › **Die attach:**
Ag sinter



- ➔ **More homogenous heat distribution**
- ➔ **Reduced thermal stress on die topside**

- ➔ **Number of cycles increased by a factor > 60**
- ➔ **Highest lifetime and performance**

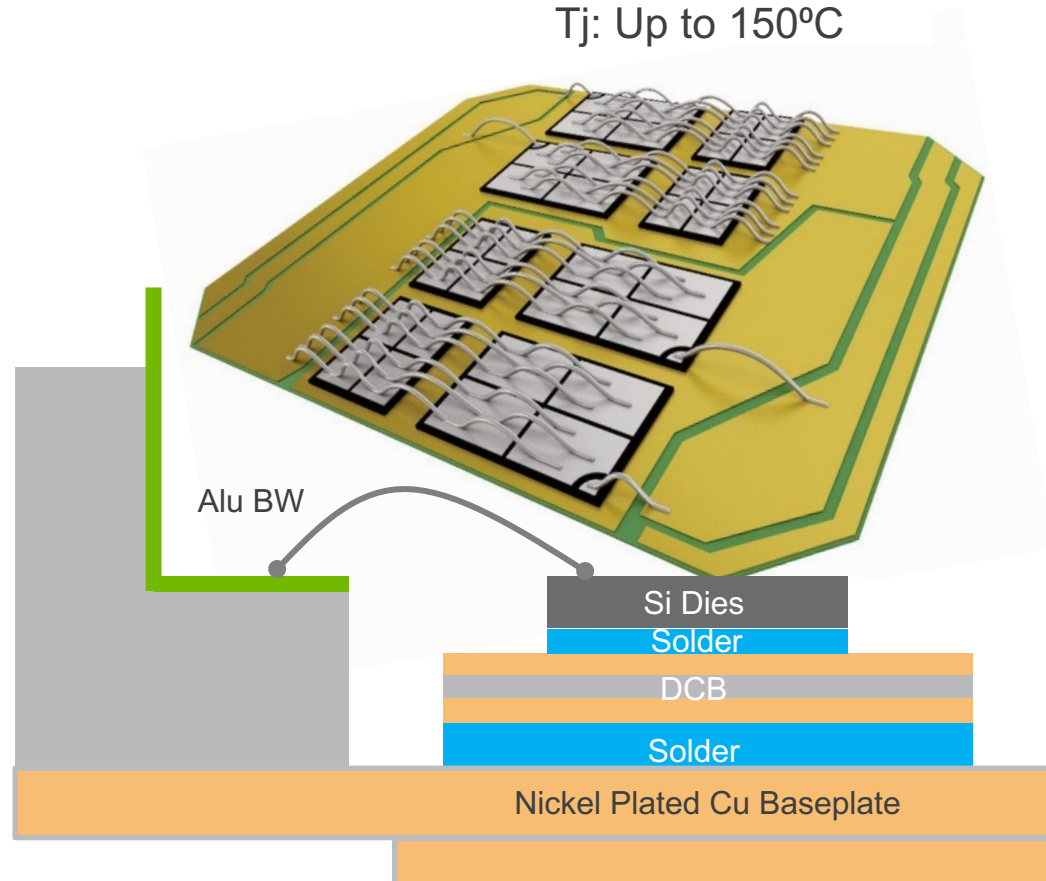


CONCLUSION

CONCLUSION: TO BENEFIT FROM THE CHANGE OF SI TO SIC BASED POWER MODULES A **CHANGE** IN ELECTRONIC PACKAGING MATERIALS IS REQUIRED

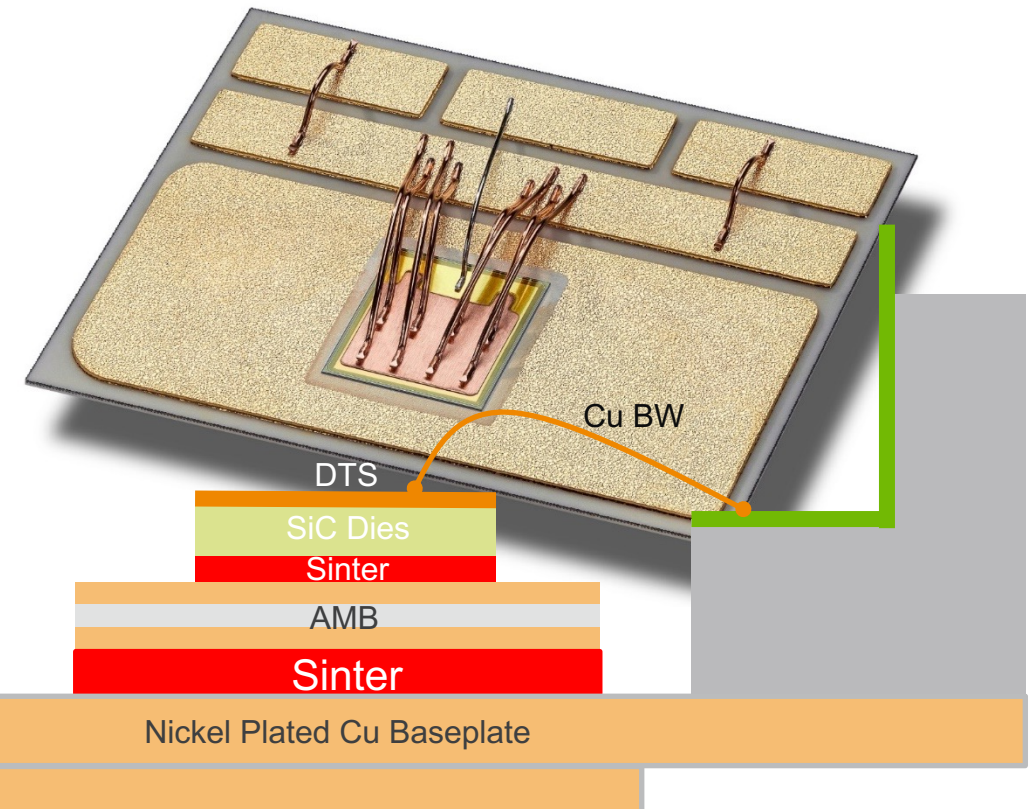
IGBT

T_j: Up to 150°C



Wide Band Gap

T_j: more than 175°C



THANK YOU

FOR YOUR INTEREST IN HERAEUS ELECTRONICS.

Let us unlock **your** potential.